



TRADEMARK OFFICE
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

**INFORMATION DISCLOSURE STATEMENT
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First Named Inventor: Yager, et al.

Group Art Unit: 1743

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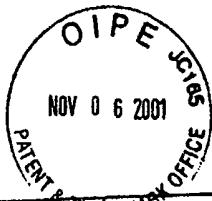
Attorney Docket No.: VGEN.P-015DV2

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95	VOLKMUTH, W.D. et al., "Trapping of branched DNA in microfabricated structures", Proc. Natl. Acad. Sci. USA 92:6887-6891, July 1995.
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Examiner John B. B. Date Considered 10/14/04